

## EXPERIMENTAL INVESTIGATION OF INELASTIC HEAVY PARTICLE COLLISIONS IN THE ENERGY RANGE 5 — 30 keV

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**Abstract:** One-electron capture and one-electron loss processes were investigated for metal ions  $Mg^+$ ,  $Fe^+$  and  $Cu^+$ . The investigation of two-electron capture processes was done for  $Fe^+$ ,  $C^+$ ,  $O^+$  and  $O_2^+$  ions. The measurements were done in the energy range of 5–30 keV and for gas targets of Ne, Kr and N<sub>2</sub>. The experimental set-up allowed measurements of the cross section values as low as  $10^{-22}$  cm<sup>2</sup>. It was found, for metal ions with the low second ionization potential, that one-electron loss cross sections could be of the same order of magnitude as those for one-electron capture process. The role of two-step processes in the formation of negative ions, influencing the measurements of two-electron capture crosssections, was analysed for the gas target thickness range of  $10^{-3}$  —  $10^{-2}$  torr · cm.

### 1. Introduction

For many years, the inelastic heavy particle collisions have been the subject of a great deal of attention. Apart from their fundamental importance, such processes have an important role in many natural phenomena and practical applications, as accelerators, ion and plasma sources, MHD and thermoionic convertors and controlled thermonuclear devices. An enormous number of experimental and theoretical investigations of these processes have been done mainly for atomic systems with simple electron configuration<sup>1, 2, 3</sup>. In order to broaden this field, the reactions which are of the particular interest, are those involving the inelastic processes of metal ions of different electron configuration. From the theoretical point of view, the experimentally determined cross sections are of special interest, in order to find out to which the metal ions processes approximate to the adiabatic conditions.

The study of the formation of negative ions in heavy particle collisions, provides a new insight into the understanding of the role of negative ions in different ionization phenomena. The experiments on the formation of nega-

tive ions in heavy particle collisions, will give more data about the existence of negative ions of different elements and about their electron affinities.

## 2. Experimental method and set-up

*Method.* Inelastic collisions of heavy particles involve great number of processes, such as charge transfer, ionization, dissociation, excitation, etc. In the present work, attention was paid to the one- and two-electron transfer and one-electron loss processes appearing in the collision of fast singly charged ions with gas targets, in the single collision conditions.

The experimental method is as follows: the beam of the incident particles, monochromated in mass number, charge state and energy, enters the interaction chamber of length  $L$ , filled with the target gas at a pressure  $p$ . Passing through the interaction chamber the particles can change their charge state in inelastic collisions with gas target particles, but retain approximately the same initial velocity, as the momentum transfer is very low at such high energies (5 — 30 keV). By measuring the yield of differently charged components of the beam passed through the interaction chamber, it is possible to determine the cross section values of the particular process taking place in the interaction. For the process, in which the incident particle changes its charge state from  $(ie)$  to  $(fe)$ , the cross section is denoted as  $\sigma_{if}$ . If one process only takes part in the formation of the component with charge  $f$ , the yield of that component is determined by the relation

$$dI_f = \sigma_{if} I_i n \cdot dx ,$$

where  $I$  is the particle beam intensity,  $n$  gas target density and  $x$  the interaction length.

Special attention had to be paid to the measurements of the low values of cross sections, as for the two-electron capture process (10/—12), where the other processes, with high probabilities<sup>4, 5)</sup>, can influence the formation of negative ions, even in the so called single collision conditions. Taking into account all processes influencing the formation of negative ions, including the reactions of fast positive, negative and neutral particles, one obtains the system of the following equations:

$$\begin{aligned} \frac{dI^+}{d(nx)} &= -(\sigma_{10} + \sigma_{1-1}) I^+ + \sigma_{01} I^0 + \sigma_{-11} I^- , \\ \frac{dI^0}{d(nx)} &= \sigma_{10} I^+ + (\sigma_{01} + \sigma_{0-1}) I^0 + \sigma_{-10} I^- , \\ \frac{dI^-}{d(nx)} &= \sigma_{1-1} I^+ + \sigma_{0-1} I^0 - (\sigma_{-11} + \sigma_{-10}) I^- . \end{aligned} \quad (1)$$

In the case when primary particles are singly-charged positive ions, the cross section for the formation of negative ions is given from the above relations by

$$\sigma_- = \frac{I^-}{nLI^+} = \sigma_{1-1} + \frac{a}{2}(nL) + \frac{b}{6}(nL)^2 + \dots, \quad (2)$$

where,  $I^+$  is primary positive ion beam intensity and

$$a = \sigma_{10}\sigma_{0-1} - \sigma_{1-1}(\sigma_{10} + \sigma_{1-1} + \sigma_{-10} + \sigma_{-11}); \quad (3)$$

$$\begin{aligned} b = & -\sigma_{10}\sigma_{0-1}(\sigma_{10} + \sigma_{01} + \sigma_{1-1} + \sigma_{-11} + \sigma_{-10} + \sigma_{0-1}) + \\ & + \sigma_{1-1}[\sigma_{10}^2 + \sigma_{-10}\sigma_{10} + \sigma_{-11}\sigma_{10} + \sigma_{10}\sigma_{01} + \sigma_{0-1}\sigma_{-10} + \\ & + (\sigma_{-10} + \sigma_{-11})^2] + \sigma_{1-1}^2(2\sigma_{10} + \sigma_{1-1} + \sigma_{-10} + 2\sigma_{-11}). \end{aligned} \quad (4)$$

By measuring the  $I^+$  and  $I^-$  intensities, one-step two-electron capture cross section  $\sigma_{1-1}$  can be determined if the gas target thickness ( $nL$ ) is so low that second and higher terms in the relation (2) may be neglected. In this case, the single collision conditions are defined as a gas target thickness, when

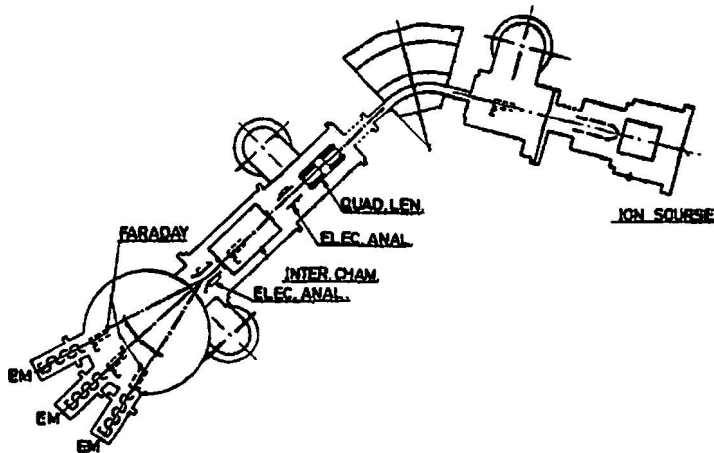


Fig. 1. Schematic diagram of the experimental arrangement.

the inequality  $\sigma_{1-1} \gg a/2(nL)$  is fulfilled, what is qualitatively different from the single collision conditions, defined by  $\lambda \gg L$  ( $\lambda$  means free path of the incident particles). For the gas target thickness, when the second term of the relation (2) is of the same order of magnitude as  $\sigma_{1-1}$  cross section and the third term is negligible, two-electron capture cross sections can be obtained by the extrapolation of the curve  $\sigma_- = f(nL)$  to  $\sigma_- = f(0)$ .

*Experimental set-up.* The experimental arrangement is shown in Fig. 1. The ion beam was produced by using a magnetron ion source<sup>9</sup> especially developed for intense ion beams of metals. One of the cathodes in the source was used as an emission filament, and the other, as a metal probe. Ion beam intensities, obtained at the entrance slit of the interaction chamber, reached up to  $10^{-4}$  A for metal ions, and up to  $10^{-5}$  A for gaseous ions. The ion beam focussing system consisted of einzel lens, a magnetic monochromator and quadrupol lenses. The gas target pressure, in the interaction chamber of length 17.8 cm varied in the range of 1 to  $5 \cdot 10^{-4}$  torr, while the pressure in

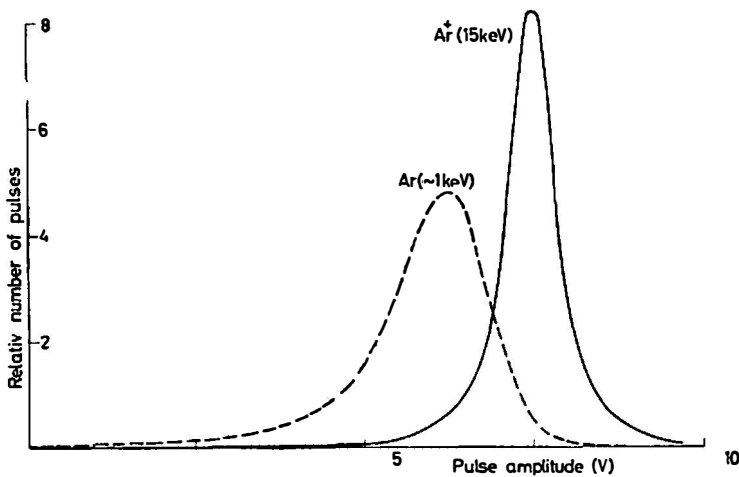


Fig. 2. Multiplier output pulse height distribution for  $\text{Ar}^+$  and Ar incident particles.

the rest of the apparatus was kept below  $1 \cdot 10^{-5}$  torr. The outside controlled slits on the interaction chamber and on the detectors allowed the control of the ion beam transmission. The beam passed through the interaction chamber and was analysed by an electrostatic plate analyser. The geometry of the analyser and the detection chamber allowed simultaneous measurements of positive, negative and neutral components of the beam. The current intensities down to  $10^{-15}$  A were measured by a vibrating reed electrometer. The secondary electron emission yield from the collector plate was taken as a measure of the neutral component yield. This method is based on the assumption on equality of secondary electron emission coefficients for ions and corresponding neutrals at high energies.

The small intensities of the interaction product particles were detected by pulse counting method, using an electron multiplier specially developed for this purpose<sup>9</sup>. It is a 26-stage Ag-Mg multiplier with a maximum gain of about  $2 \cdot 10^9$  electrons per incident particle. At the maximum gain, the mul-

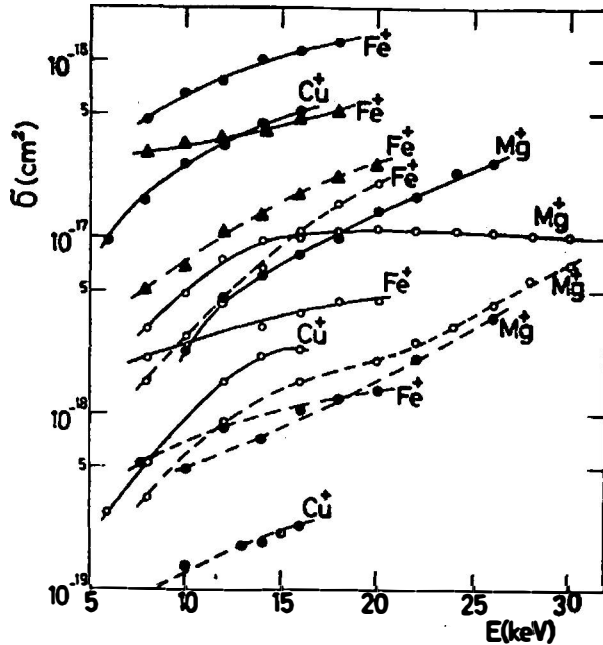


Fig. 3. One-electron capture  $\sigma_{10}$  (full lines) and one-electron loss  $\sigma_{12}$  (dashed lines) cross section:  $\circ$  — Ne target;  $\bullet$  — Kr Target;  $\Delta$  —  $N_2$  target.

tiplier was in a pulse saturated mode of operation, with main pulse amplitude of about 7 V. So the whole spectrum (shown in Fig. 2.), could be easily registered without additional amplification. Counting efficiency was determined by pulse losses over a few entrance dynodes of the multiplier. For high energy ions,  $E > 5$  keV, counting efficiency was close to 100%. Low noise of about 3 puls/min., enabled high sensitivity of the detector.

### 3. Results and discussion

*One-electron capture  $\sigma_{10}$  and one-electron loss  $\sigma_{12}$  cross sections for metal ions.* One-electron capture  $\sigma_{10}$  and one-electron loss  $\sigma_{12}$  cross section were measured for metal ions  $Mg^+$ ,  $Fe^+$  and  $Cu^+$  and gas targets Ne, Kr and  $N_2$ .

The results obtained for  $\sigma_{10}$  and  $\sigma_{12}$  cross sections for the investigated elements are shown in Figs. 3 and 4. All measured cross section values increase with energy, as it is expected for this velocity region  $v < 10^8$  cm/s. The values are in accordance with the magnitudes of the energy defect for the particular pairs of the interacting particles. The only deviation is noticeable in the case

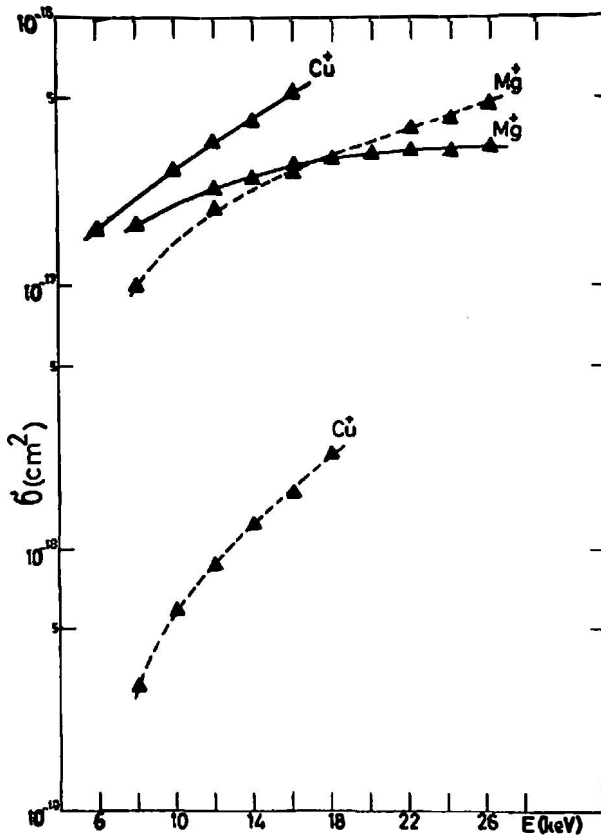


Fig. 4. Comparison of one-electron capture  $\sigma_{10}$  (full lines) and one-electron loss  $\sigma_{12}$  (dashed lines) cross sections for  $\text{Mg}^+/\text{N}_2$  and  $\text{Cu}^+/\text{N}_2$ .

of  $\text{N}_2$  gas target, where  $\sigma_{10}$  and  $\sigma_{12}$  cross section values are higher than those obtained for inert gas targets, and corresponding energy defects. Similar effects for molecular gas targets were noticed in some earlier works<sup>8, 9)</sup>. The leveling of the  $\sigma_{10} = f(E)$  curve for  $\text{Mg}^+/\text{Ne}$ ,  $\text{N}_2$ , in this energy range, could not be explained simply by the adiabatic theory. The comparison of the experimentally obtained results for  $\sigma_{10}$  and  $\sigma_{12}$  cross sections showed that the probability of one-electron loss process increased with decreasing of the second ionization potential of the primary ion. In some cases, as for  $\text{Mg}^+$ , with the lowest second ionization potential in the group of the investigated metal ions,  $\sigma_{12}$  cross sections are of the same order of magnitude as  $\sigma_{10}$ , what is evident in Fig. 4. For comparison,  $\sigma_{12}$  and  $\sigma_{10}$  cross section for  $\text{Cu}^+$ , with the highest second ionization potential, are included in Fig. 4.

*Two-electron capture cross sections  $\sigma_{1-1}$ .* The formation of negative ions in two-electron capture process (10/—12) was investigated for ions  $C^+$ ,  $O^+$ ,  $O_2^+$  and metal ion  $Fe^+$ . The results are shown in Fig. 5, and for comparison Fogel's results are included<sup>9</sup>. As it can be seen, the cross section values increase with energy, showing a few maxima. These maxima appear below the

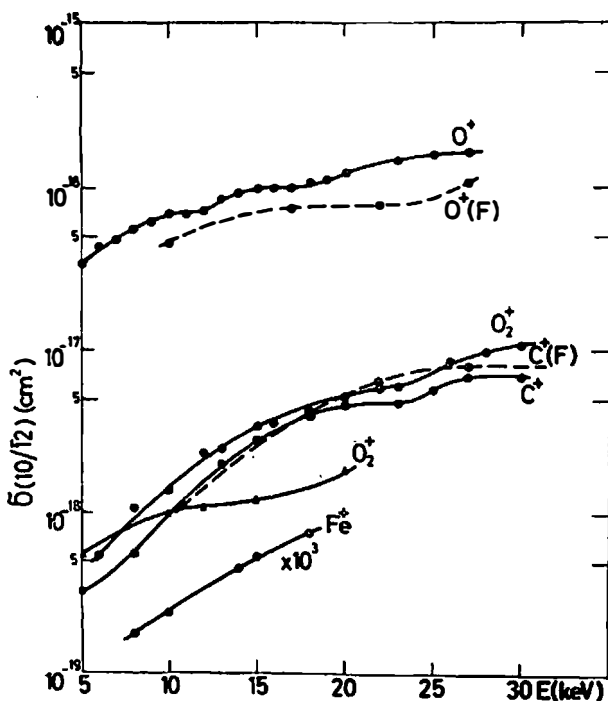


Fig. 5. Two-electron capture cross sections  $\sigma_{1-1}$  (full lines): ● — Kr target;  $\Delta$  —  $N_2$  target. Fogel's results<sup>9</sup> are included as dashed lines.

maximum corresponding to the ground state ions, and could be attributed to the reactions of excited ions present in the primary ion beams<sup>11</sup>). The cross section values for different elements increase with the magnitudes of their electron affinities. It is interesting to notice, that for the investigated gaseous ions, two-electron capture process is of rather high probability in comparison with that for one-electron capture and one-electron loss process.

Two-electron capture process, for  $Fe^+$  has a very low probability in this energy range. The obtained results for  $Fe^+/Kr$  case, are in a good agreement with the empirical curve given by Kozlov and Bondar<sup>12</sup>) for the process (10/—12), as shown in Fig. 6.

Special attention was paid to the analysis of  $\sigma_- = f(nL)$  curves, in order to detect the influence of two-step processes on the formation of negative ions. Linear dependence of the measured  $\sigma_-$  on  $(nL)$ , was found in the case of  $C^+/Kr$  only, indicating the influence of two-step processes on the formation

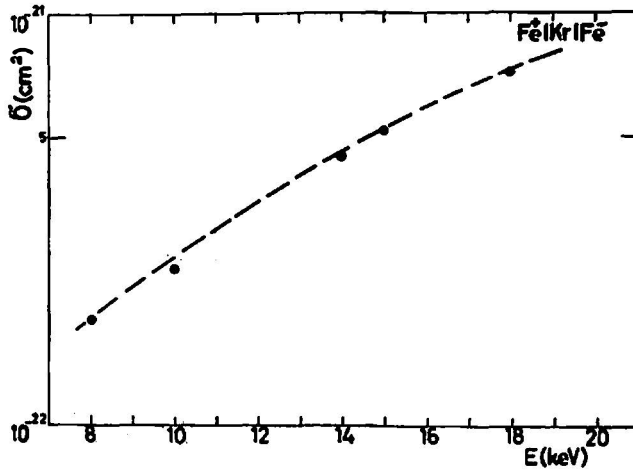


Fig. 6. Comparison of the experimental results for two-electron capture cross section  $\sigma_{1-1}$  for  $Fe^+/Kr$  (points) with the empirical curve (dashed line), given by Kozlov and Bondar<sup>19</sup>.

of negative  $C^-$  ions. The analysis of these curves, for the gas target thickness range of  $10^{-3} - 10^{-2}$  torr · cm, revealed that dependence of  $\sigma_- = f(nL)$  could be represented by the relation (2) reduced to the following expression:

$$\sigma_- = \sigma_{1-1} + \frac{1}{2} \sigma_{10} \sigma_{0-1} (nL).$$

Two-electron capture cross sections  $\sigma_{1-1}$  for different energies were determined by the extrapolation of the curves  $\sigma_- = f(nL)$  to  $\sigma_- = f(0)$ .

In the other investigated cases, the influence of two-step processes on the measurements of  $\sigma_{1-1}$  was in the range of the experimental error.

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## EKSPERIMENTALNO ISPITIVANJE NEELASTIČNIH SUDARA TEŠKIH ČESTICA U OPSEGU ENERGIJA 5 — 30 keV

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### S a d r Ź a j

Ekspperimentalno su ispitani sudarni procesi zahvata i otkidanja jednog elektrona za jone metala  $Mg^+$ ,  $Fe^+$  i  $Cu^+$ , kao i procesi zahvata dva elektrona sa formiranjem negativnog jona za jone  $Fe^+$ ,  $C^+$ ,  $O^+$  i  $O_2^+$ . Efikasni preseći za ove procese izmereni su u uslovima jednostrukog sudara, primenom metoda interakcije snopa brzih jona sa gasnom metom (neon, kripton, azot), u opsegu energija 5 — 30 keV. Primenjena eksperimentalna tehnika omogućila je merenje efikasnih preseka u opsegu  $10^{-15}$  —  $10^{-22}$   $cm^2$ .

Rezultati su pokazali da efikasni preseći za gubitak jednog elektrona mogu biti istog reda veličine kao i efikasni preseći za zahvat jednog elektrona, u slučaju jona metala sa niskim drugim jonizacionim potencijalom. Analizirani su uslovi uticaja dvostepenih procesa na formiranje negativnih jona, pri merenju efikasnih preseka za zahvat dva elektrona u opsegu gustina gasne mete od  $10^{-3}$  —  $10^{-2}$  torr · cm.